

# A $V_{DD}$ Independent Temperature Sensor Circuit with Scaled CMOS Process

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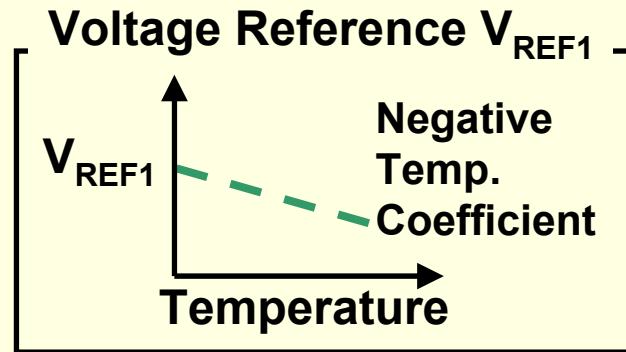
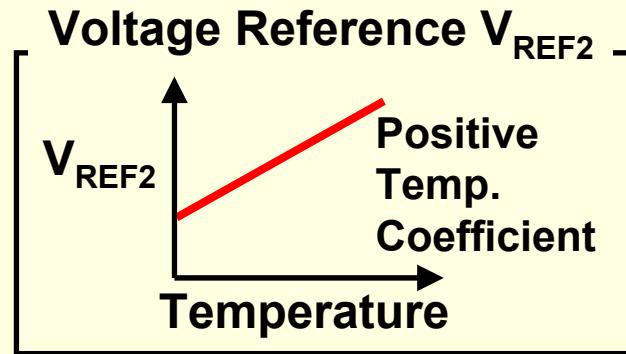
<sup>2</sup>Dawn Enterprise Co. Ltd.

# Motivation and Purpose

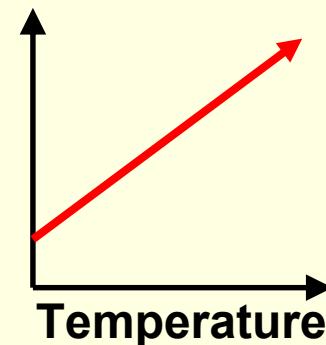
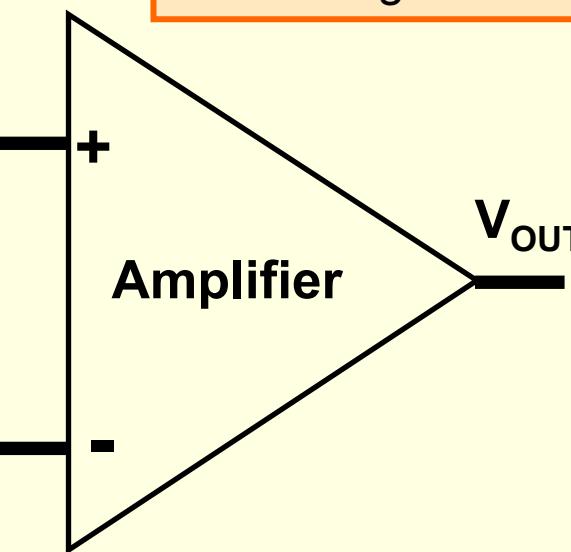
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- ◆ A supply-voltage independent on-chip CMOS temperature sensor circuit is one of important analog sub-circuits for thermally sensitive integrated circuit systems
- ◆ We propose a  $V_{DD}$  independent temperature sensor circuit with a standard CMOS process
- ◆ We are aiming realization of on-chip high accuracy temperature sensor applying CMOS voltage reference with scaled CMOS process

# Temperature Sensor Scheme

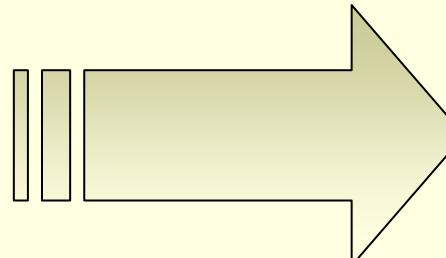


In theory, we think the effect by threshold voltage variation can be canceled



※  $\alpha$  : Gain of amplifier

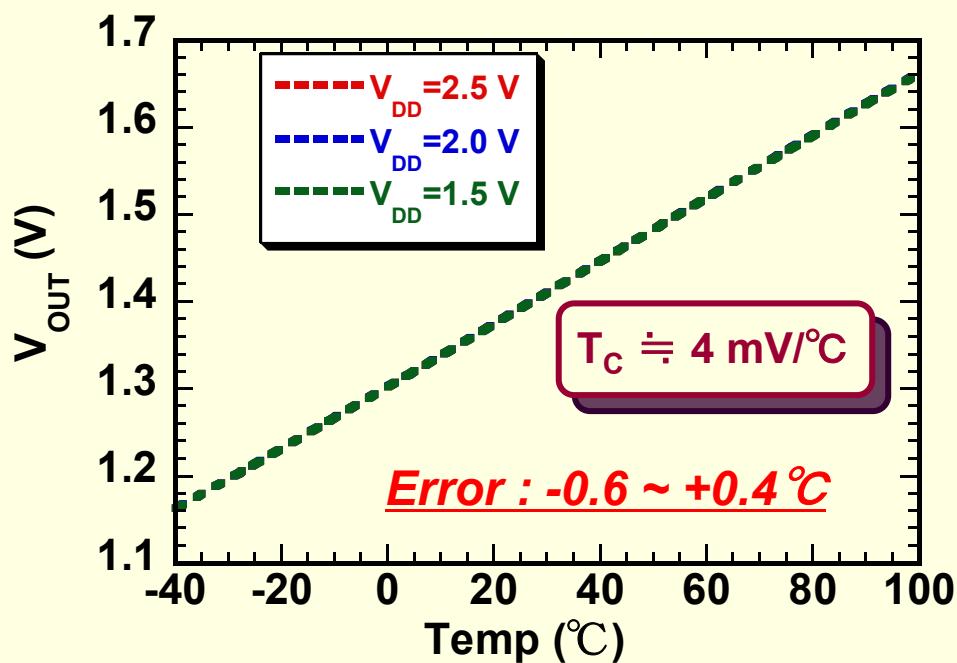
$$\begin{aligned}V_{REF2} &= V_{TH0} + T_{C_2} T \\V_{REF1} &= V_{TH0} + T_{C_1} T\end{aligned}$$



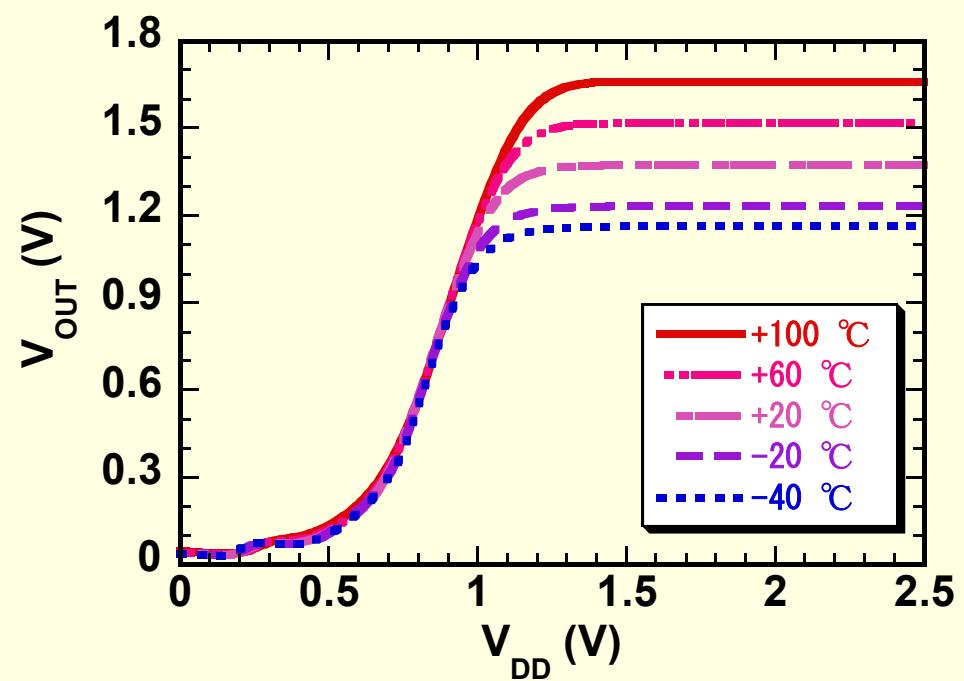
$$\begin{aligned}V_{OUT} &= \alpha(V_{REF2} - V_{REF1}) \\&= \alpha(T_{C_2} T - T_{C_1} T) \\&= \alpha(T_{C_2} - T_{C_1}) T\end{aligned}$$

# Simulation Results

## Temp dependences of $V_{OUT}$



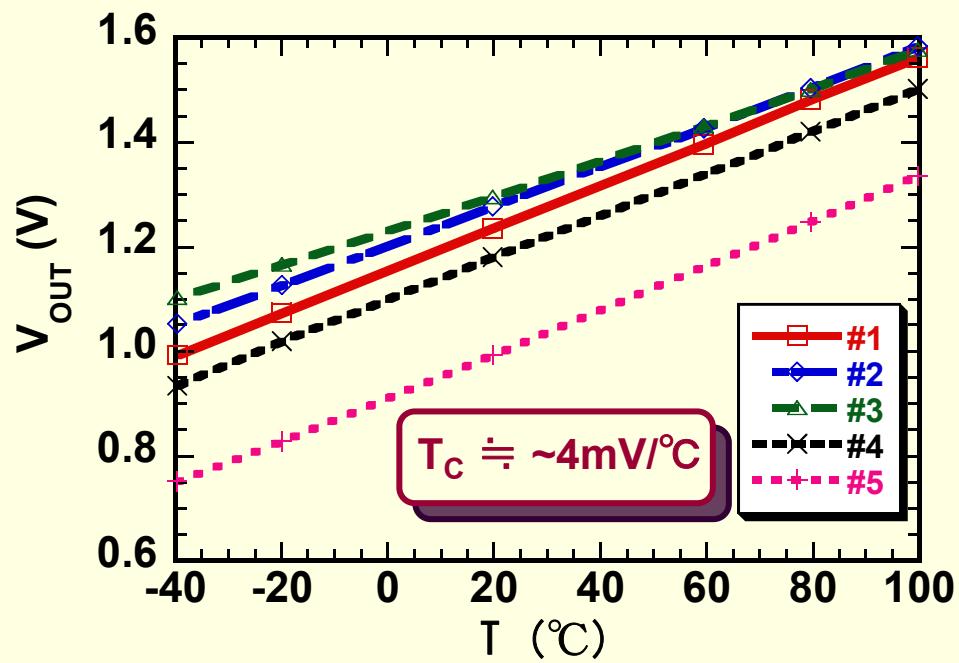
## $V_{DD}$ dependences of $V_{OUT}$



$$Error = \frac{V_{OUT} - (\text{Regression Line})}{T_c}$$

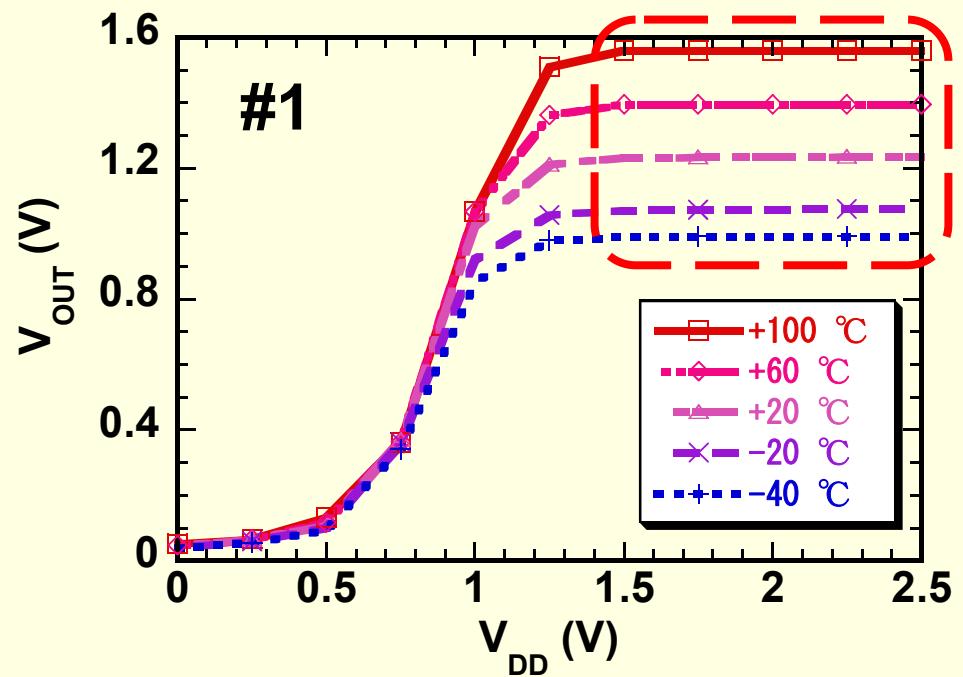
# Measurement Results

## Temp dependences of $V_{OUT}$



Calibration Error : -1 ~ 2  $^{\circ}\text{C}$  (-20 ~ +100  $^{\circ}\text{C}$ )  
: -0.6 ~ 0  $^{\circ}\text{C}$  (+20 ~ +80  $^{\circ}\text{C}$ )

## $V_{DD}$ dependences of $V_{OUT}$



$V_{DD}$  variation  $\Delta V_{OUT}$  : ~ 0.9  $^{\circ}\text{C}$   
(converting to temp)